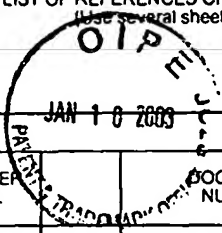
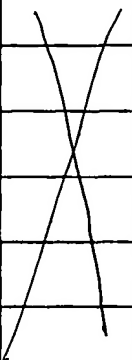


FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		ATTY DOCKET NO. 00862.022498		APPLICATION NO. Not Yet Assigned	
APPLICANT <div style="text-align: center;">Taka Yonehara, et al.</div>		FILING DATE <div style="text-align: center;">Currently herewith</div>		GROUP <div style="text-align: center;">Not Yet Assigned</div>	

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
Bu	5,206,749	4/27/93	Zavracky et al.	359	59	<div style="writing-mode: vertical-rl; transform: rotate(180deg);"> 31800 U.S. PTO 10/059144 01/31/02 </div>	
Bu	5,256,562	10/26/93	Vu et al.	437	86		
Bu	5,811,348	9/22/98	Matsushita, et al.	438	455		
Bu	6,107,213	8/22/00	Tayanaka, et al.	438	762		
Bu	5,985,742	11/16/99	Henley, et al.	438	515		
Bu	5,856,229	1/5/99	Sakaguchi, et al.	438	406		
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
Bu	9-312349	12/2/97	Japan			Abstract	
Bu	886 300	12/23/98	EP				
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
<div style="border: 1px solid black; width: 100%; height: 100%; position: relative;"> <div style="position: absolute; top: 0; left: 0; right: 0; bottom: 0; border: 1px solid black; transform: rotate(45deg); transform-origin: center;"></div> </div>							
EXAMINER <u>Brook Kebede</u>				DATE CONSIDERED <u>2/2/2004</u>			

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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <small>(Use several sheets if necessary)</small>		ATTY DOCKET NO. 00862.022498.		APPLICATION NO. 10/059,144		
		APPLICANT TAKAO YONEHARA, et al.				
		FILING DATE January 31, 2002		GROUP 2812		
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BU	6,075,280	06/13/00	Yung et al.	257	620	
BU	6,136,668	10/24/00	Tamaki, et al.	438	462	
BU	6,186,384	02/13/01	Sawada	225	2	
BU	6,465,329	10/15/02	Glenn	438	462	
BU	2002/0076904	06/20/02	Imler	438	462	
BU	2002/0100941	08/01/02	Yonehara, et al.	257	359	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER Brook K. Gedd			DATE CONSIDERED 2/2/2004			

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U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

AUG 19 2002

PRIORITY DOCKET NO. 00862.022498

APPLICATION NO. 10/059,144

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)APPLICANT **TAKAO YONEHARA, et al.**FILING DATE **January 31, 2002**GROUP **2812**

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Bu		6,190,937	02/20/2001	Nauagawa, et al.	438	67	
Bu		6,222,513	03/10/1998	Howard, et al.	345	84	
Bu		6,258,698	07/10/2001	Iwasaki, et al.	438	455	
Bu		6,306,729	10/23/2001	Sauaguchi, et al.	438	458	
Bu		6,331,208	12/18/2001	Nishida, et al.	117	89	
Bu		6,342,433	01/29/2002	Ohmi, et al.	438	455	
Bu		6,382,292	05/07/2002	Ohmi, et al.	156	584	

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Bu	EP	1 122 794	08/08/2001	Europe			
Bu	EP	858 110	08/12/1998	Europe			
Bu	EP	849 788	06/24/1998	Europe			
Bu	JP	11-316397	11/16/1999	Japan	G02F		Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

Bu		Shimoda, T., et al, "Surface Free Technology By Laser Annealing (SUFTLA)" International Electron Devices Meeting 1999. IEDM. Technical Digest. Washington, DC, Dec. 5 to 8, 1999, New York, NY: IEEE, US, August 1, 1999 (1999-08-01), pages 289 to 292, XP000933199 ISBN: 0-7803-5411-7.					

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